

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10717496	SAINT ETIENNE ET AL.
	Examiner	Art Unit
	Cehic, Kenan	2616

SEARCHED

Class	Subclass	Date	Examiner
370	516,517,519,238,395.21,253,235,230,230.1,508,516,389	11/8/2007	KC
370	235,252	5/23/2008	kc

SEARCH NOTES

Search Notes	Date	Examiner
Inventorship Search	11/5/2007	KC
Consulted with SPE Kwang Yao	11/7/2007	KC
EAST Text search	11/6/2007	KC
IEEE Xplorer	11/8/2007	KC
Consulted with SPE Kwang Yao	5/23/2008	kc
Update Search	5/23/2008	kc

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	See Interference Search printout		